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Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

JC6 /572

U.S. UTILITY Patent Application

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APPLICATION NO.	CONT/PRIOR	CLASS	SUBCLASS	ART UNIT	EXAMINER
09/854177	D	438		2822	

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TITLE
Method and system for detecting metal contamination on a semiconductor wafer

PTO-2040
12/99

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ISSUING CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
INTERNATIONAL CLASSIFICATION			
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☐ TERMINAL DISCLAIMER	DRAWINGS			CLAIMS ALLOWED	
	Sheets Drwg.	Figs. Drwg.	Print Fig.	Total Claims	Print Claim for O.G.
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☐ The term of this patent shall not extend beyond the expiration date of U.S Patent. No. _____	_____ (Primary Examiner) _____ (Date)			ISSUE FEE	
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